

Form PTO-1449 U.S. Department of Commerce
 (REV. 2-82) Patent and Trademark Office

Atty. Docket No.
 36179/US-2-475387-30

Serial No.
 10/577,562

**INFORMATION DISCLOSURE STATEMENT
 BY APPLICANT
 (Use several sheets if necessary)**

Applicant(s)
 Seok-Hyun Yun et al.

Filing Date
 April 27, 2006

Confirmation No.
 3634

U.S. PATENT DOCUMENTS

*Exam. Init.	Document No.							Date	Name	Class	Subclass	Filing Date if Appropriate
	4	5	3	3	2	4	7	August 6, 1985	Epworth eeeeeeeeee			
	6	7	4	1	3	5	5	May 25, 2004	Drabarek eeeeeeeeee			
2005	0	0	7	5	5	4	7	April 7, 2005	Wang eeeeeeeeee			
2005	0	0	8	3	5	3	4	April 21, 2005	Riza et al. eeeeeeeeee			
	3	9	7	3	2	1	9	August 3, 1976	Tang et al.			
	3	9	8	3	5	0	7	September 28, 1976	Tang et al.			
2006	0	1	0	3	8	5	0	May 18, 2006	Alphonse et al. eeeeeeeeeee			
	4	8	9	2	4	0	6	January 9, 1990	Waters eeeeeeeeee			
	5	7	1	6	3	2	4	February 10, 1998	Toida φ			
	6	4	5	9	4	8	7	October 1, 2002	Chen et al.φ			
2002	0	0	9	3	6	6	2	July 18, 2002	Chen et al. φ			
	6	3	5	9	6	9	2	March 19, 2002	Groot φφφ			
	6	9	0	3	8	2	0	June 7, 2005	Wang φφφφ			
2006	0	2	4	4	9	7	3	November 2, 2006	Yun et al. φφφφφφ			
	5	2	2	8	0	0	1	July 13, 1993	Birge et al. φφφφφφφ			
	6	6	8	7	0	3	6	February 3, 2004	Riza φφφφφφ			
	4	4	2	8	6	4	3	January 31, 1984	Kay φφφφφφ			
	4	9	6	5	5	9	9	October 23, 1990	Roddy et al. φφφφφφφ			

Examiner

Date Considered

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		4	3	0	3	3	0	0	December 1, 1981	Pressiat et al.			
		6	8	3	9	4	9	6	January 4, 2005	Mills et al.			
2004	0	1	3	3	1	9	1	July 8, 2004	Momiuchi et al. ΦΦΦΦΦΦΦ				
	5	8	4	0	0	7	5	November 24, 1998	Mueller et al. ΦΦΦΦΦΦΦ				
2003	0	2	1	6	7	1	9	November 20, 2003	DeBenedictis et al. ΦΦΦΦΦΦΦ				
2006	0	1	5	5	1	9	3	July 13, 2006	Leonardi et al. ΦΦΦΦΦΦΦΦΦ				
2003	0	1	9	9	7	6	9	October 23, 2003	Podoleanu et al. ΦΦΦΦΦΦΦΦΦ				
2004	0	2	1	2	8	0	8	October 28, 2004	Okawa et al. ΦΦΦΦΦΦΦΦΦ				

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		Document No.							Date	Country	Class	SubClass	Translator Yes No
		9	6	2	8	2	1	2	September 19, 1996	WIPO ΦΦΦΦΦΦΦΦΦΦΦ			
		0	9	3	3	0	9	6	August 4, 1999	European ΦΦΦΦΦΦΦΦΦΦΦΦ			
		4	1	0	5	2	2	1	September 12, 1991	Germany			
		0	1	0	8	5	7	9	February 8, 2001	WIPO ΦΦΦΦΦΦΦ			
		9	9	0	5	4	8	7	February 4, 1999	WIPO ΦΦΦΦΦΦΦ			
200	5	0	8	2	2	2	5	September 9, 2005	WIPO ΦΦΦΦΦΦΦΦΦΦ				
200	4	0	3	4	8	6	9	April 29, 2004	WIPO ΦΦΦΦΦΦΦΦΦΦ				

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	0	3	0	5	2	4	7	8	June 26, 2003	WIPO ΦΦΦΦΦΦΦΦΦΦ			
	200	7	0	3	8	7	8	7	April 5, 2007	WIPO ΦΦΦΦΦΦΦΦΦΦ			

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